

# The Performance Study of CIGS Solar Cell by SCAPS-1D Simulator

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**Abstract:** The reference structure was simulated by SCAPS-1D simulator. The simulation result showed the effect of CIGS thickness, band gap and effect of EBR on the cell performance. From the simulation it could be seen that all parameters were sharply affected below CIGS thickness of 1000 nm due to increase of recombination velocity at back contact and poor absorption. Open circuit voltage was improved by CIGS thickness and band gap. Reference structure showed 18.78% efficiency after simulation with CIGS thickness of 3000 nm and band gap of 1.15 eV. The back electron reflector (EBR) had been inserted to reduce the effect of back contact recombination. With EBR cell performance was significantly improved. The proposed structure showed 19.30% efficiency with CIGS thickness of 1000 nm.

## Introduction

CIGS are enrolled as an effective alternative to silicon technology. One of the important advantages based on CIGS is the reduction of material usage and thereby reducing cost of production. The past performance of CIGS was reported to 20.3% [26]; which is close to silicon whose performance is nearly 25%. For improving performance of CIGS solar cell it is desirable to understand the basic factors limiting the electrical parameters of the cell. The main aim of this work was to study the various parameters of CIGS solar cell. The simulation was done using SCAPS-1D simulator. Various parameters such as absorber layer thickness, band gap and effect of EBR were examined. The parameters were simulated using SCAPS-1D simulator and their influence on electrical parameters of CIGS solar cell was analyzed.

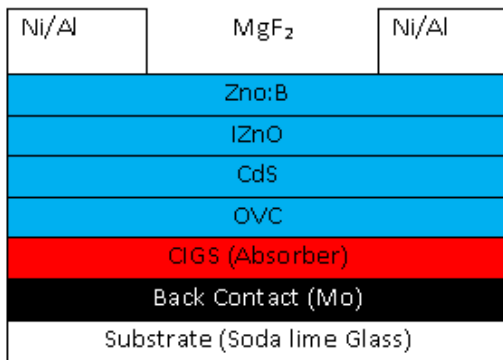


Figure 1(a) Reference Structure

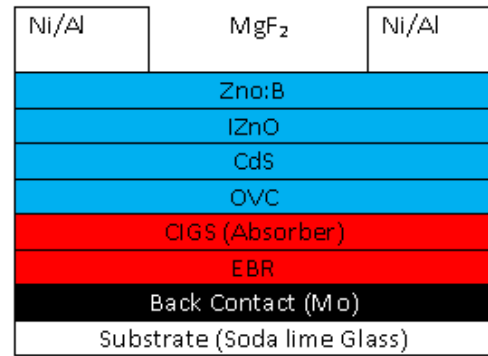


Figure 1(b) Proposed Structure

## Cell structure

The structure was simulated using SCAPS-1D simulator. The main part of the cell is CIGS absorber layer and CdS buffer layer. The thin layer OVC is formed between interface states of absorber layer and buffer layer. OVC is normally beneficial for CIGS because of shifting electrical junction from high recombination interface between absorber and buffer layer. As a result recombination rate is reduced [1]. ZnO intrinsic layer and Boron doped ZnO are deposited on the top of the buffer layer. These two layers are commonly considered as a Transparent conducting oxide (TCO). The major drawback of ZnO: Al is absorption loss which leads to decrease in quantum efficiency of CIGS solar cell near infrared region. Therefore Boron doped ZnO would be more beneficial of CIGS solar cell [2]. Transparent conducting oxide is protected with anti-reflected MgF<sub>2</sub> layer to increase the absorption of photons in the absorber layer.

**Numerical modeling and parameters for simulation**

Simulations can be used to provide the information to interpret measurements and to analyze the potential merits of cell structure. Different software such as SCAPS-1D[22], ASA[3], PC-1D[4], AMPS-1D[18] have been developed for describing the performances of thin film solar cells. SCAPS-1D is widely used simulation program for CdTe and CIGS based solar cells. Single level defect is introduced in each layer. To pin Fermi level at CIGS/OVC and OVC/CDS layer interface neutral defects were introduced at 0.6 eV below the conduction band. The effect of series and shunt resistance was not taken in to the consideration. Band discontinuity at the interfaces between different layers was considered small and avoided. The solar spectrum AM 1.5 was used for the numerical simulation. The temperature was set at 300K. The following parameters were used for numerical simulation.

*Table 1. Layer Properties [28]*

Parameters	EBR	CIGS	OVC	CdS	iZnO	ZnO:B
W (nm)	10	100-3000	30	50	200	400
E <sub>g</sub> (e V)	1.4	Graded	1.3	2.4	3.3	3.3
X (e V)	4.5	4.5	4.5	4.45	4.55	4.55
ε/ε <sub>0</sub>	13.6	13.6	13.6	10	9	9
N <sub>c</sub> (cm <sup>-3</sup> )	2.2 x10 <sup>18</sup>	2.2 x10 <sup>18</sup>	2.2 x10 <sup>18</sup>	1.3 x10 <sup>18</sup>	3.1x10 <sup>18</sup>	3.0x10 <sup>18</sup>
N <sub>v</sub> (cm <sup>-3</sup> )	1.8 x10 <sup>19</sup>	1.5 x10 <sup>19</sup>	1.5 x10 <sup>18</sup>	9.1 x10 <sup>18</sup>	1.8 x10 <sup>19</sup>	1.8 x10 <sup>19</sup>
v <sub>e</sub> (cm/s)	10 <sup>7</sup>	3.9 x10 <sup>7</sup>	3.9 x10 <sup>7</sup>	3.1 x10 <sup>7</sup>	2.4 x10 <sup>7</sup>	2.4 x10 <sup>7</sup>
v <sub>h</sub> (cm/s)	10 <sup>7</sup>	1.4 x10 <sup>7</sup>	1.4 x10 <sup>7</sup>	1.6 x10 <sup>7</sup>	1.3 x10 <sup>7</sup>	1.3 x10 <sup>7</sup>
μ <sub>e</sub>	100	100	10	72	100	100
μ <sub>h</sub>	25	12.5	1.50	20	31	31
Doping (cm <sup>-3</sup> )	2 x10 <sup>19</sup>	5 x 10 <sup>16</sup> (A)	10 <sup>13</sup> (A)	5 x10 <sup>17</sup> (D)	10 <sup>17</sup> (D)	10 <sup>20</sup> (D)

*Table 2. Bulk defect Properties [28]*

Parameters	EBR	CIGS	OVC	CdS	i ZnO	ZnO:B
N( cm <sup>-3</sup> )	10 <sup>14</sup> (D)	10 <sup>14</sup> (D)	10 <sup>14</sup> (D)	5 X 10 <sup>16</sup> (A)	10 <sup>16</sup> (A)	10 <sup>16</sup> (A)
ε <sub>e</sub> (cm <sup>2</sup> )	10 <sup>-15</sup>	10 <sup>-15</sup>	10 <sup>-15</sup>	10 <sup>-15</sup>	10 <sup>-15</sup>	10 <sup>-15</sup>
ε <sub>h</sub> (cm <sup>2</sup> )	10 <sup>-11</sup>	10 <sup>-11</sup>	10 <sup>-11</sup>	5 X 10 <sup>-13</sup>	5 X 10 <sup>-13</sup>	5 X 10 <sup>-13</sup>

*Table 3. Properties of Interface [28]*

Interface	CIGS/OVS	OVC/CDS
ΔE <sub>c</sub> (e V)	0.6	0.6
N (cm <sup>-3</sup> )	10 <sup>11</sup> (N)	3x 10 <sup>13</sup> (N)
ε <sub>e</sub> (cm <sup>2</sup> )	10 <sup>-15</sup>	10 <sup>-15</sup>
ε <sub>h</sub> (cm <sup>2</sup> )	10 <sup>-15</sup>	10 <sup>-15</sup>

### Simulation analysis and result:

#### Effect of CIGS thickness on the performance of Solar cell

The thickness of CIGS was set at 3000nm. Other parameters were remained constant with variation of CIGS thickness. The CIGS band gap was kept constant at 1.15 e V. The figure (2) shows the influence of CIGS thickness on different electrical parameters of the cell. It could be observed from the result that there is a sudden reduction of all electrical parameters for reducing CIGS thickness below 1000 nm. The short circuit current density ( $J_{sc}$ ) decreased abruptly by reducing CIGS thickness below 1000 nm. Recombination of photoelectrons at back contact was the reason of this. Photons having short wavelength deeply penetrate in to absorber layer and can create electron-hole pairs at back contact. In this zone recombination rate is very high. This may leads to lower the short circuit current density from  $34.092197 \text{ mA/cm}^2$  to  $25.463094 \text{ mA/cm}^2$  when CIGS thickness was reduced from 1000 nm to 100 nm.

For ultrathin thickness  $V_{oc}$  lesson due to reduction of the junction. The debase of  $V_{oc}$  and  $J_{sc}$  drive to reduce efficiency of CIGS cell. The cell efficiency reduces from 16.93 % for 1000nm thickness of absorber layer to 8.93% for the thickness of 100 nm. The main reason behind this is only few photons are absorbed by absorber layer as the CIGS thickness reduces. As a result efficiency of solar cell reduced. All parameters of solar cell remained constant for CIGS thickness greater than 1000nm. The  $J_{sc}$  increased from the value  $34.092197 \text{ mA/cm}^2$  to  $36.734819 \text{ mA/cm}^2$  when CIGS thickness was increased from 1000 nm to 3000 nm. This leads to the cell efficiency from 16.93 % to 18.78 %. The quantum efficiency reaches 90% at CIGS thickness of 1000 nm. As the thickness was increased from 1000 nm more photons can be absorbed by absorber layer which can improve the cell performance.

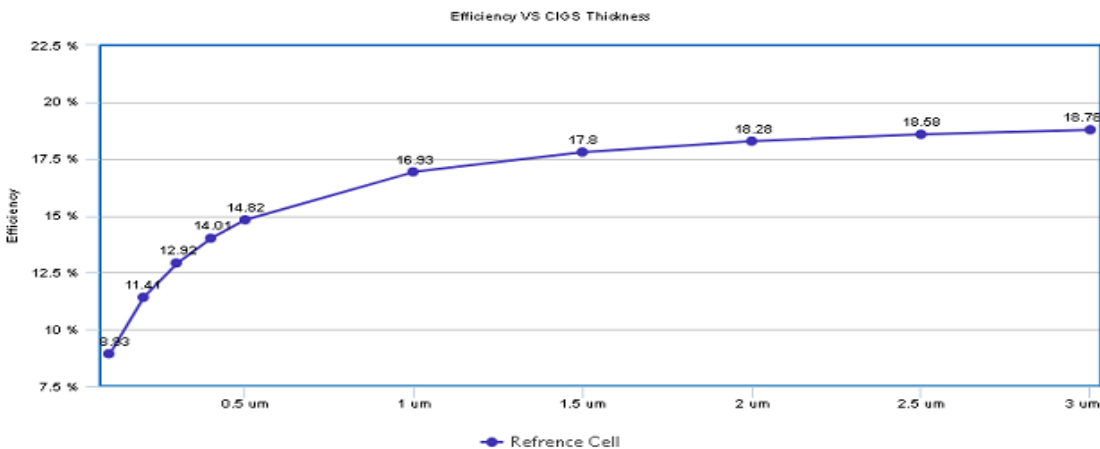


Figure 2 (a)  $J_{sc}$  VS CIGS thickness

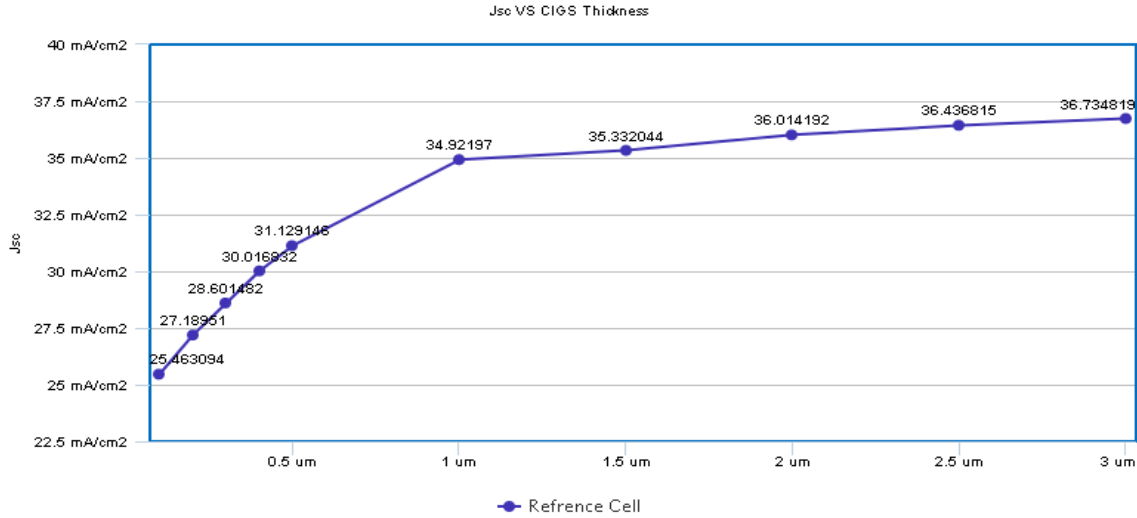


Figure 2 (b) Efficiency VS CIGS thickness

### Grading effect on Performance of CIGS solar cell

CIGS band gap could be changed from 1 eV to 1.65 eV based on gallium proportion. The gallium dependency of band gap can be described by following equation.

$$E_g [eV] = 1.02 + 0.67x + bx (x - 1) [8].$$

Where x denotes the gallium content in CIGS layer, x is the ratio of Ga / (Ga + In). The coefficient b is known as optical bowing coefficient. The band gap was assumed to be varied in accordance with gallium content in absorber layer. All parameters of CIGS layer and parameters of other layers were kept constant. From the simulation it could be seen that Voc increased with increase of band gap for  $E_g < 1.25$  eV. However the increment of Voc was not in proportional form with band gap. The relation of Voc was linear for band gap  $< 1.25$  eV ( $X < 0.3$ ). The relation became nonlinear for band gap having value  $> 1.25$  eV ( $X > 0.3$ ). However open circuit voltage remains constant with high Ga concentration. This was mainly because of increment of recombination rate in space charge region (SCR). From simulation result it could be seen that short circuit current density decreased sharply with increase of gallium content but strongly dependent on absorber layer thickness. For  $W < 1000$  nm due to combined effect of increase in band gap and decrease in absorption coefficient decrement of Jsc was severe. The efficiency and fill factor increased with increase of band gap for  $E_g < 1.25$  eV. Above this value if band gap is increased by adding gallium concentration will decrease cell performance. These results seem to be good in comparison with experimental result obtained from different literature. The cell shows excellent efficiency with  $E_g = 1.15$  eV ( $X = 0.3$ ) [13]. From the study of Rau et al. [14] and Hanna et al. [9] it could be concluded that increment of band gap by adding Ga concentration can induce deformity in CIGS. These deformity gain degrade cell performance when band gap exceeds beyond 1.15 eV ( $X = 0.3$ ). Figure (3) and Figure (4) shows variations of electrical parameters due to change in band gap.

### Performance improvement with EBR:

The most affected parameter is short circuit current density by changing of CIGS thickness especially for ultrathin absorber ( $< 1000$ nm) as the electron is captured by back contact. Due to capture of electron at back contact Jsc reduces below 1000 nm thickness of absorber layer. With the help of ultrathin layer (EBR) between CIGS and Mo it would be possible to keep photo electrons away from interface. The back electron reflector can keep away electrons from CIGS/Mo

interface. As a result short circuit current density increases with increment of absorber layer thickness. Back electron reflector is able to increase all parameters of cell. The efficiency gain is about 2 % with EBR having thickness of 10 nm when absorber layer thickness is 1000 nm. The figure (5) shows gain in  $J_{sc}$  and efficiency due to different EBR thickness by varying the thickness of CIGS.

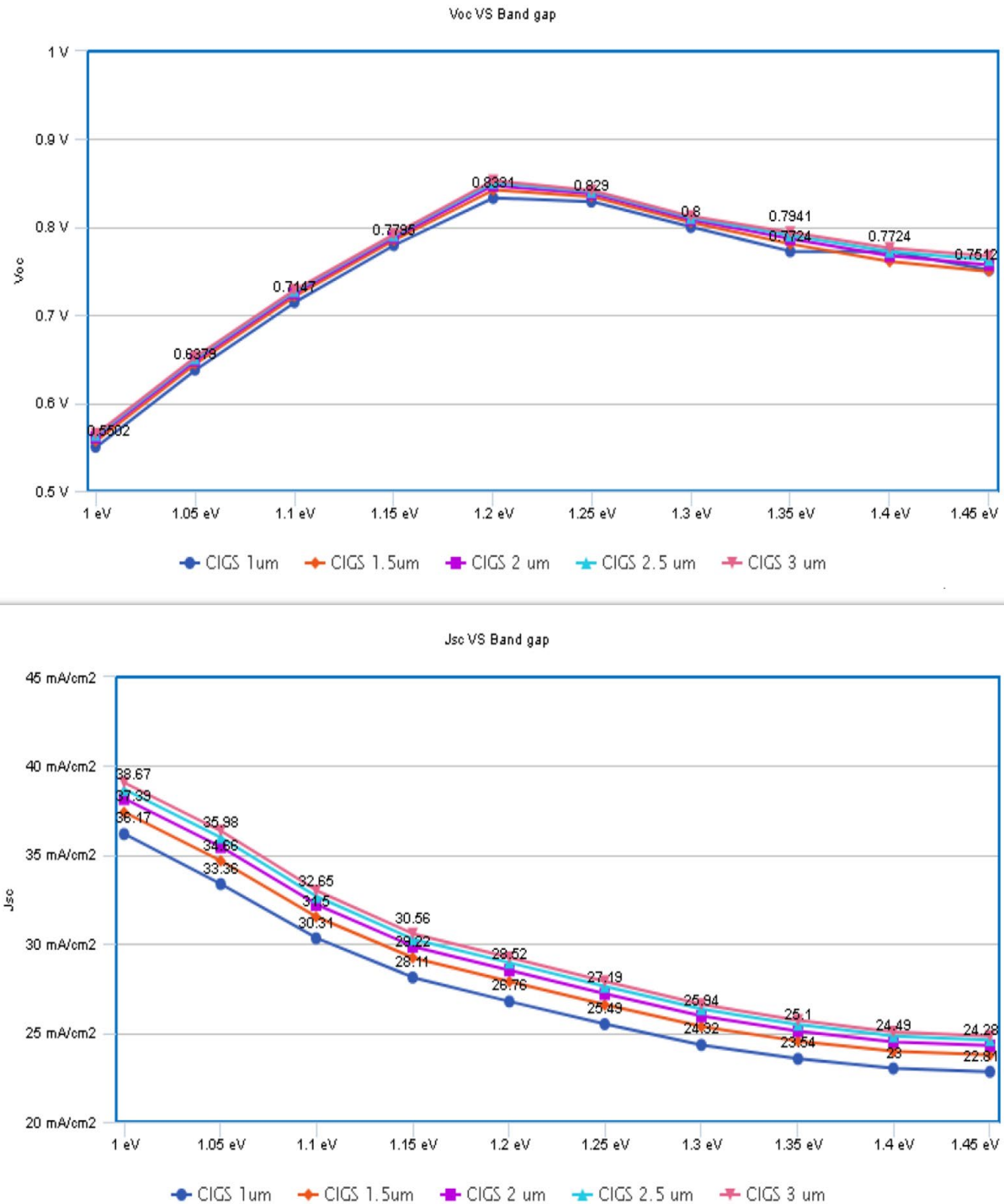


Figure 3. Effect of CIGS band gap on  $V_{oc}$  and  $J_{sc}$  by varying CIGS thickness

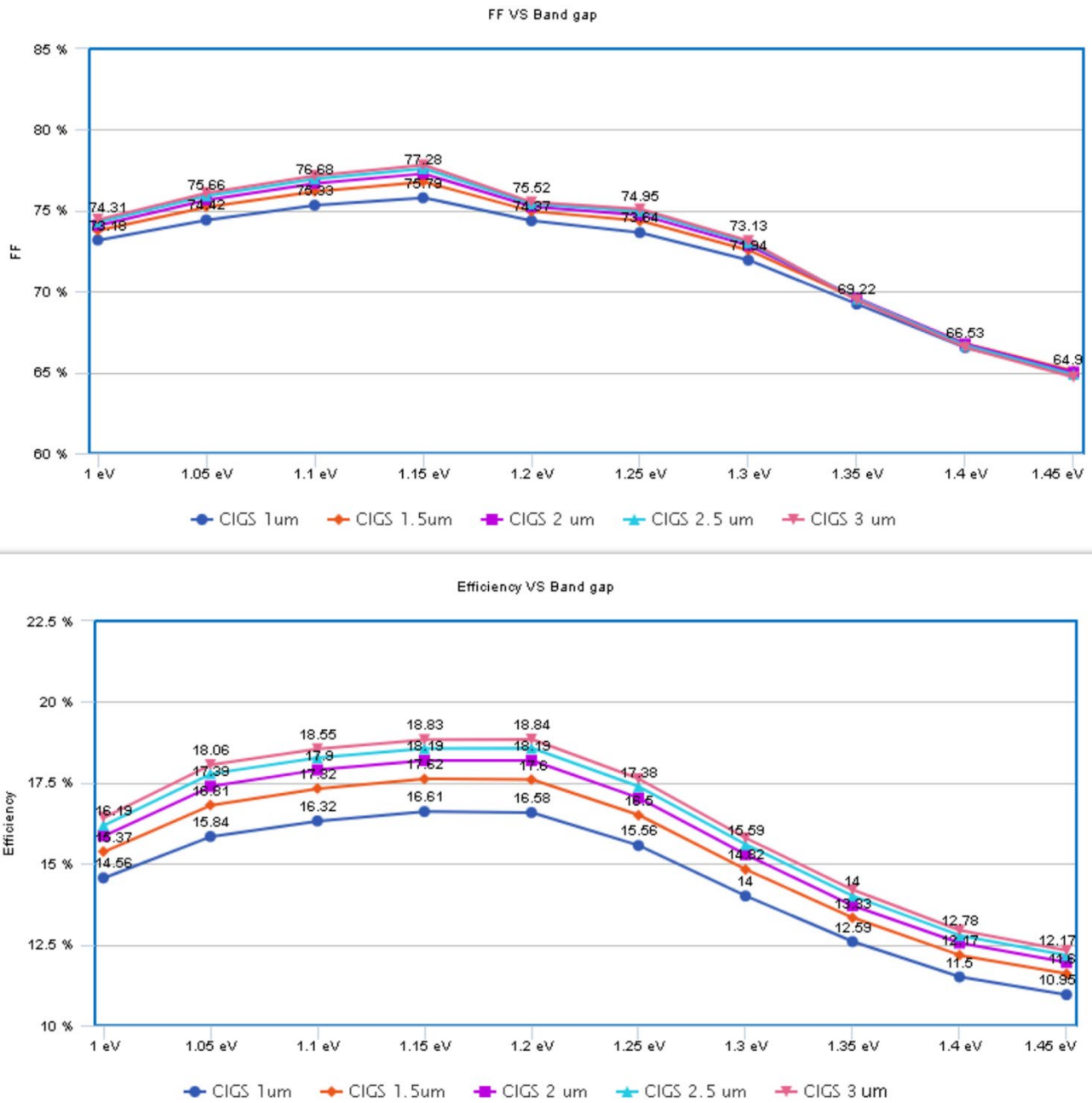


Figure 4. Effect of CIGS band gap on Fill factor and Efficiency by varying CIGS thickness

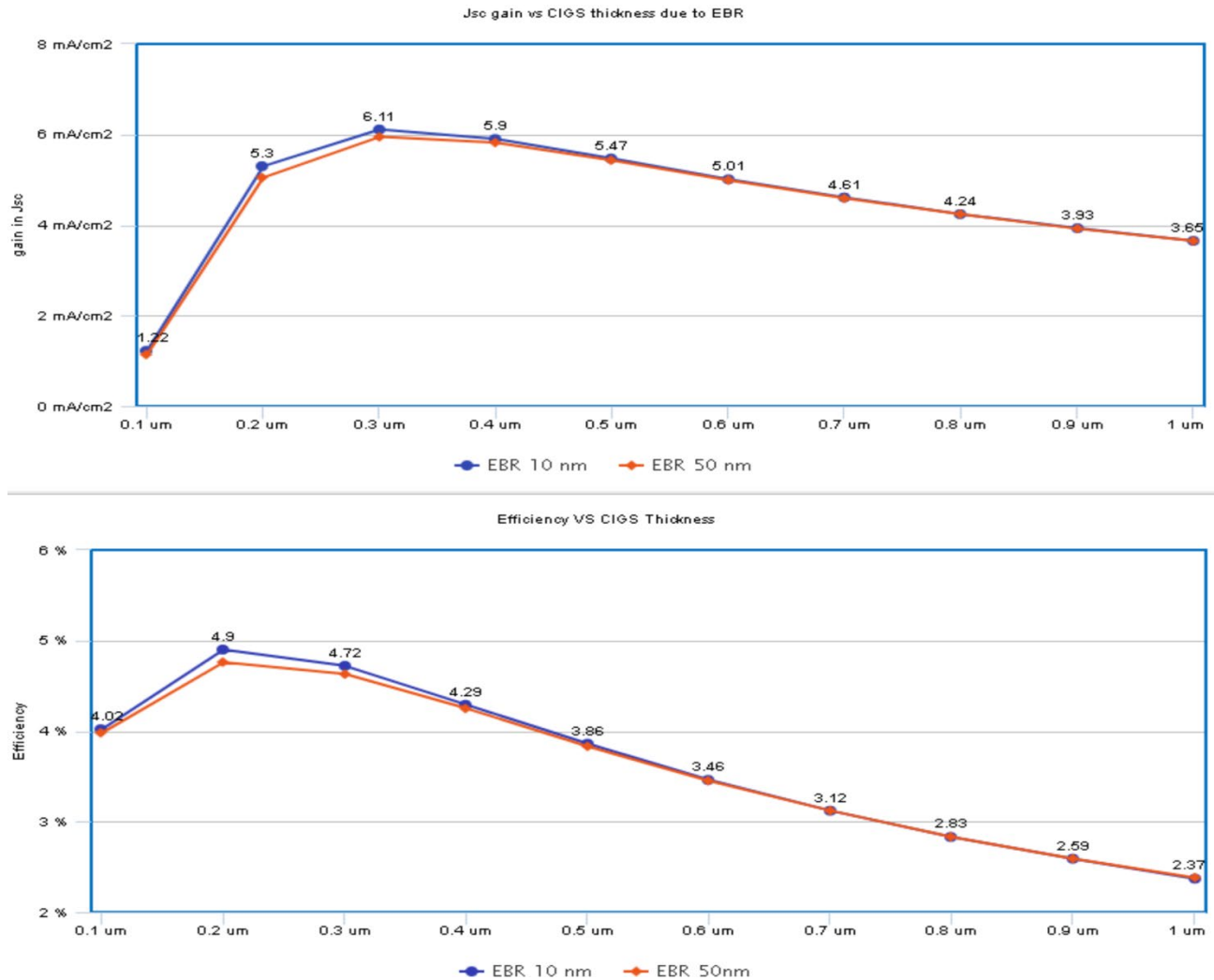


Figure 5. Gain in Jsc and Efficiency with back electron reflector by changing CIGS thickness

**Conclusion**

The thickness of CIGS layer, band gap and effect of EBR were analyzed using SCAPS-1D simulator. Following results could be obtained after simulation.

1. All parameters of cell are affected by varying CIGS thickness; short circuit current density degrades when thickness reduces from 1000 nm to 100 nm because of increment of recombination at CIGS/Mo interface.
2. The Ga grading can enhance solar cell performance. Jsc reduces drastically with increment of Ga in absorber. The relation between Voc and band gap is linear for  $E_g < 1.25$  eV. With increase in gallium concentration in absorber can enhance efficiency for  $E_g < 1.2$  eV. Above this value increase in gallium concentration in absorber layer can reduce the cell efficiency. At  $E_g = 1.15$  cell shows the highest efficiency.
3. Back electron reflector can improve the cell performance. The efficiency is gained by 2 % with the presence of EBR with thickness of 10 nm when absorber layer thickness is 1000 nm.

Table 4. Performance parameters of Reference and Proposed cell

Parameters of cell	Reference cell	Cell with EBR (Proposed)
Thickness of CIGS ( $\mu\text{m}$ )	1.0	1.0
Open circuit voltage(V)	0.6567	0.6727
Jsc ( $\text{mA}/\text{cm}^2$ )	34.092197	37.746186
FF (%)	75.62	76.03
Efficiency (%)	16.93	19.30

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